

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/709,087	<b>Applicant(s)/Patent under Reexamination</b> CHANG, HUNG-YI
	<b>Examiner</b> Mark J. Beauchaine	<b>Art Unit</b> 3653

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See	attached.		MJB